



ALPHA & OMEGA
SEMICONDUCTOR

AON7524

30V N-Channel AlphaMOS

General Description

- Latest Trench Power AlphaMOS (α MOS LV) technology
- Very Low $R_{DS(ON)}$ at 2.5V V_{GS}
- Low Gate Charge
- ESD protection
- RoHS and Halogen-Free Compliant

Application

- DC/DC Converters

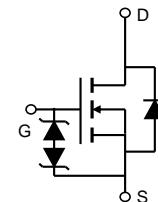
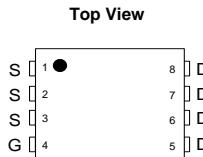
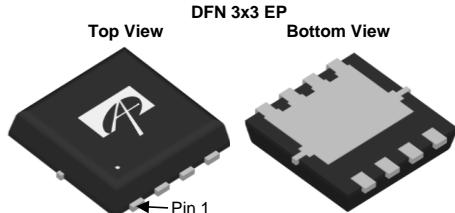
Product Summary

V_{DS}	30V
I_D (at $V_{GS}=10V$)	28A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 3.3mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 4mΩ
$R_{DS(ON)}$ (at $V_{GS}=2.5V$)	< 5.8mΩ

Typical ESD protection

HBM Class 3B

100% UIS Tested
100% R_g Tested



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ^G $T_C=25^\circ C$	I_D	28	A
		22	
Pulsed Drain Current ^C	I_{DM}	112	
Continuous Drain Current ^C $T_A=25^\circ C$	I_{DSM}	25	A
		20	
Avalanche Current ^C	I_{AS}	28	A
Avalanche energy $L=0.05mH$ ^C	E_{AS}	20	mJ
V_{DS} Spike	V_{SPIKE}	36	V
Power Dissipation ^B $T_C=25^\circ C$	P_D	32	W
		12.8	
Power Dissipation ^A $T_A=25^\circ C$	P_{DSM}	3.1	W
		2	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	30	40	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		60	75	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	3.1	3.9	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{V}_{\text{GS}}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_J=125^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 10\text{V}$			± 10	μA
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	0.4	0.8	1.2	V
$\text{R}_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$ $T_J=125^\circ\text{C}$		2.6	3.3	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=18\text{A}$		3	4	
		$\text{V}_{\text{GS}}=2.5\text{V}, \text{I}_{\text{D}}=16\text{A}$		4.4	5.8	
g_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		103		S
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.62	1	V
I_{S}	Maximum Body-Diode Continuous Current ^G				28	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		2250		pF
C_{oss}	Output Capacitance			800		pF
C_{rss}	Reverse Transfer Capacitance			65		pF
R_g	Gate resistance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, \text{f}=1\text{MHz}$	1.5	3.0	4.5	Ω
SWITCHING PARAMETERS						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		37	50	nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			16	22	nC
Q_{gs}	Gate Source Charge			3.2		nC
Q_{gd}	Gate Drain Charge			5.2		nC
$\text{t}_{\text{D}(\text{on})}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		5		ns
t_{r}	Turn-On Rise Time			3		ns
$\text{t}_{\text{D}(\text{off})}$	Turn-Off Delay Time			47.5		ns
t_{f}	Turn-Off Fall Time			11.3		ns
t_{rr}	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		16		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		23		nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\text{JJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

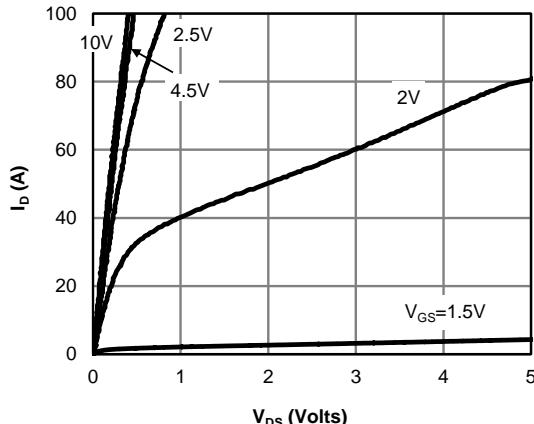
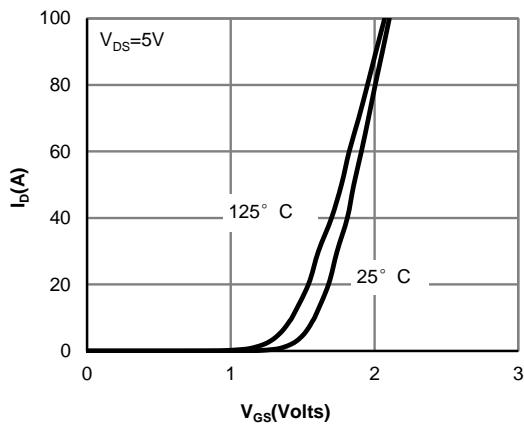
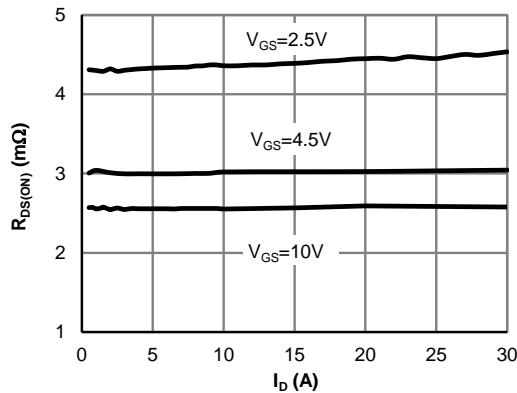
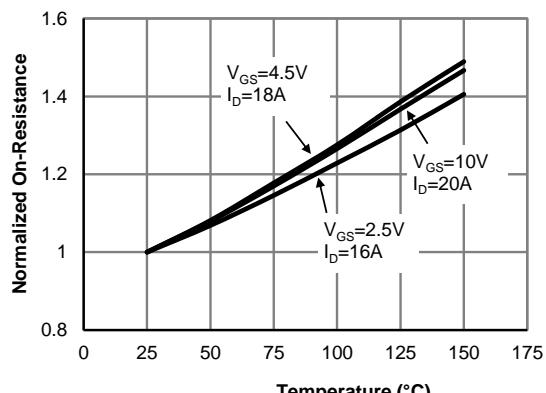
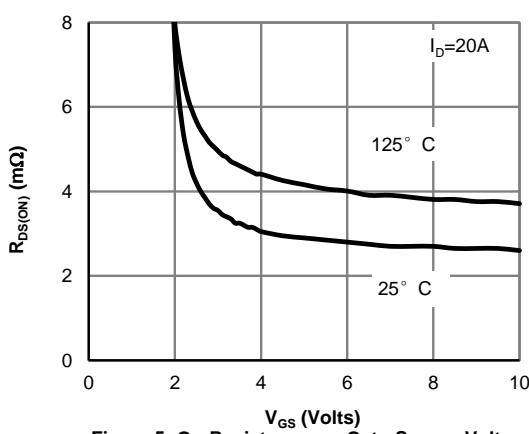
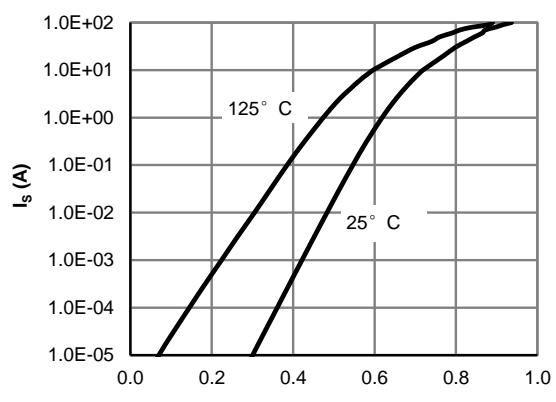
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{\text{J}(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

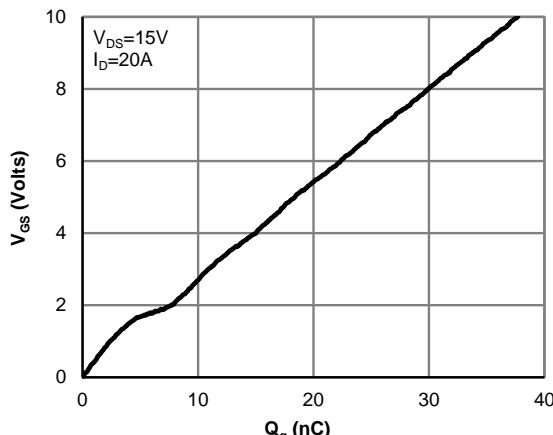
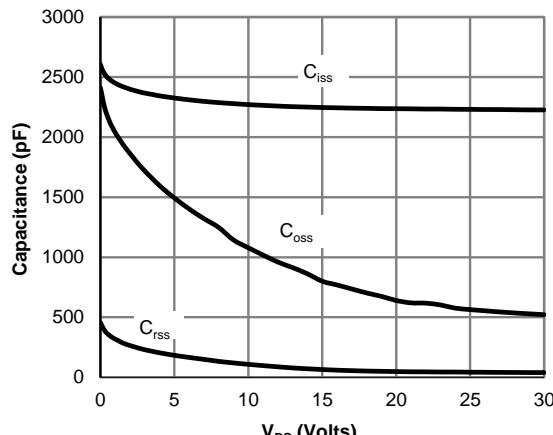
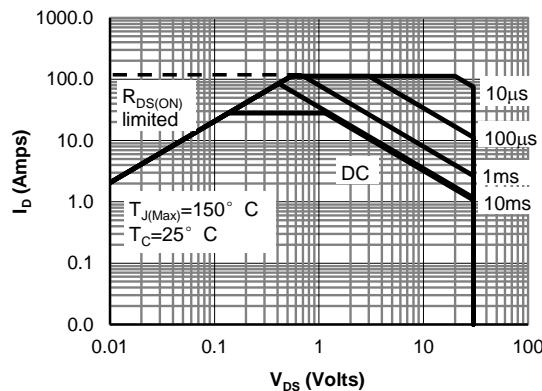
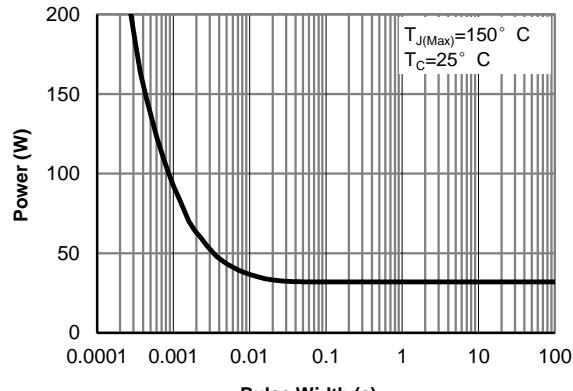
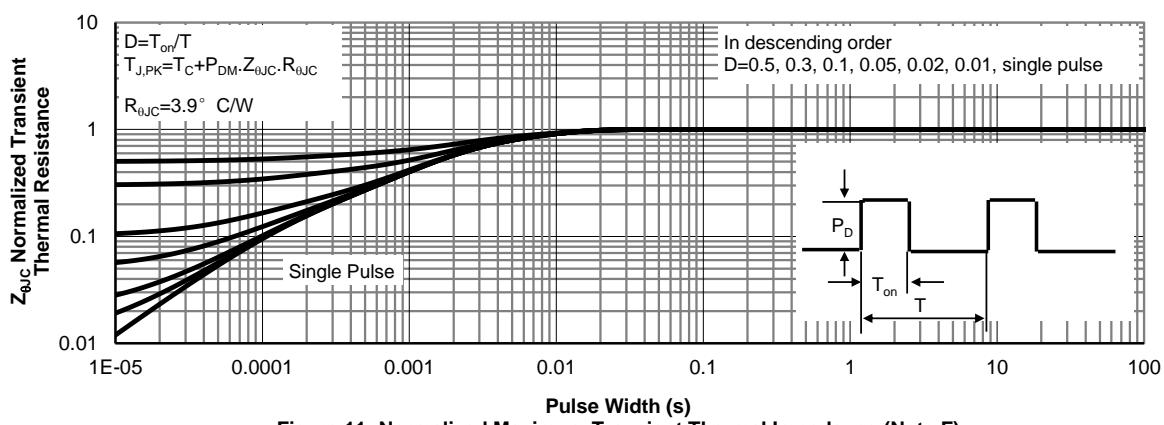
G. The maximum current rating is package limited.

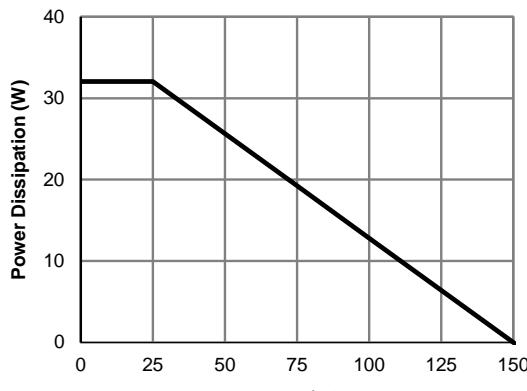
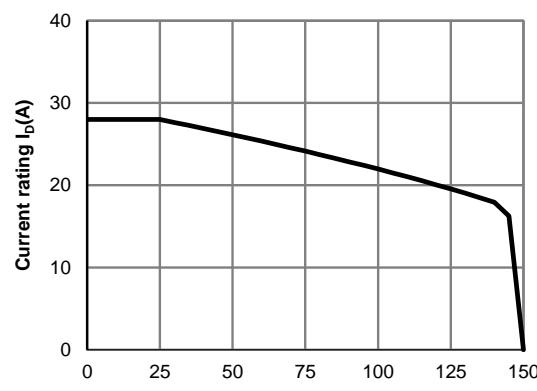
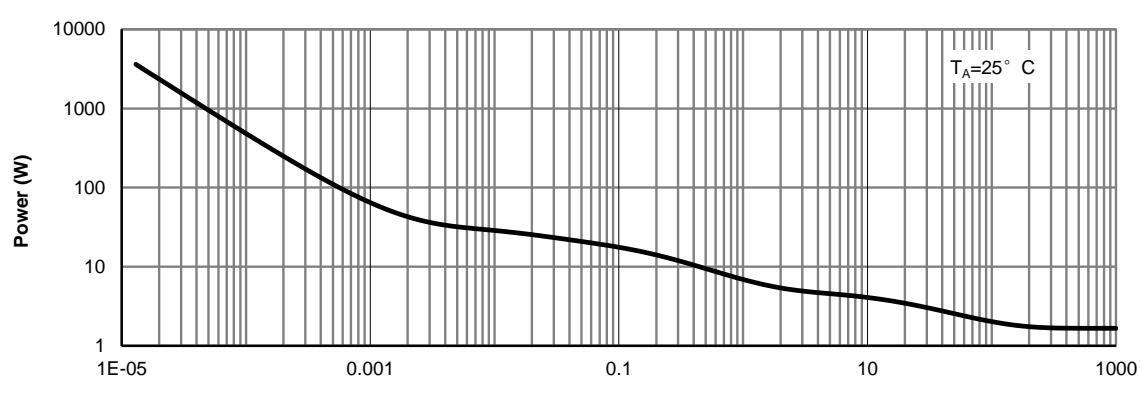
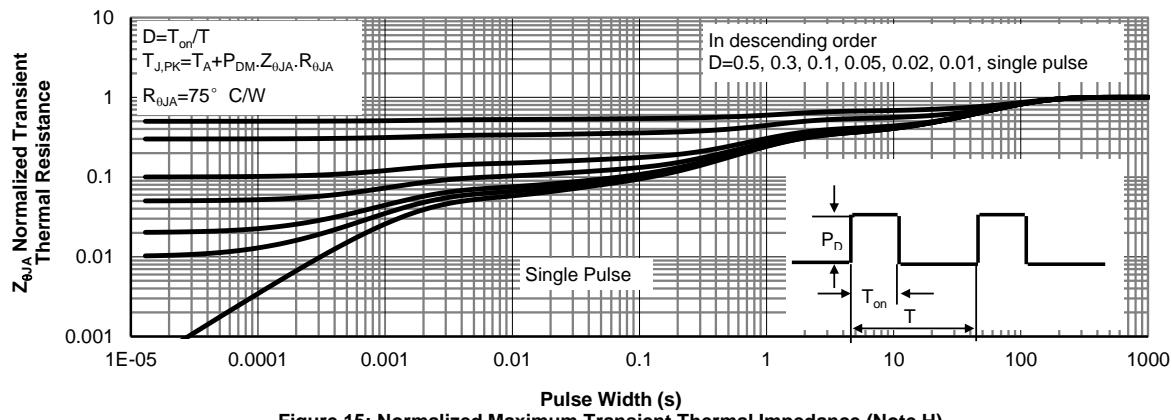
H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

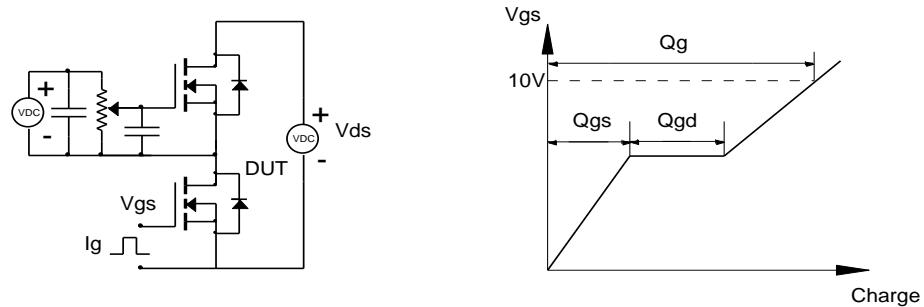
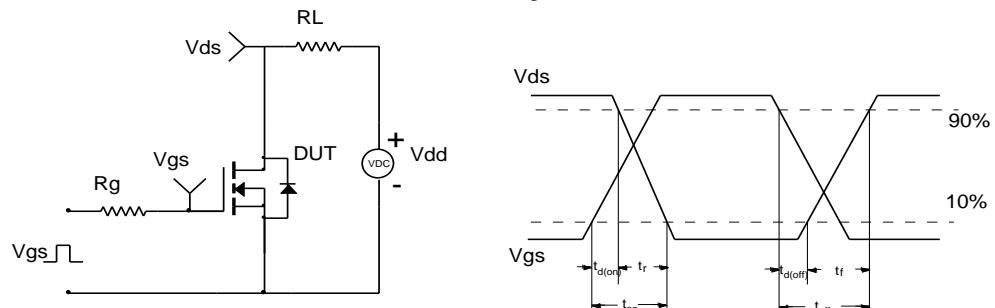
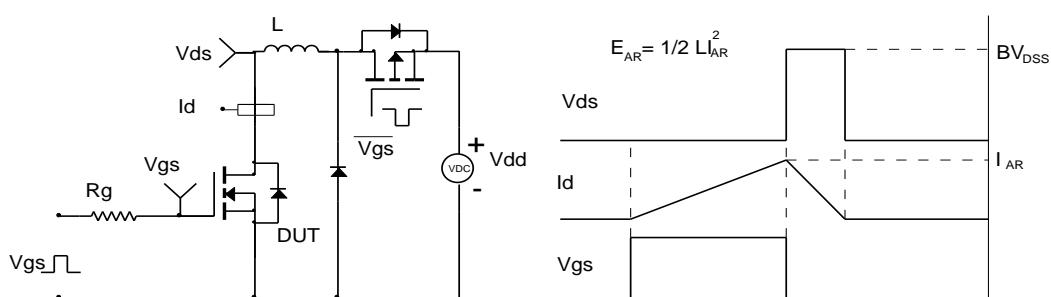
APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO MAKE CHANGES TO PRODUCT SPECIFICATIONS WITHOUT NOTICE. IT IS THE RESPONSIBILITY OF THE CUSTOMER TO EVALUATE SUITABILITY OF THE PRODUCT FOR THEIR INTENDED APPLICATION. CUSTOMER SHALL COMPLY WITH APPLICABLE LEGAL REQUIREMENTS, INCLUDING ALL APPLICABLE EXPORT CONTROL RULES, REGULATIONS AND LIMITATIONS.

AOS' products are provided subject to AOS' terms and conditions of sale which are set forth at:
http://www.aosmd.com/terms_and_conditions_of_sale

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 12: Power De-rating (Note F)

Figure 13: Current De-rating (Note F)

Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
